

Search Notes

Application/Control No.

10/761,436

Examiner

Vivian Nelson

Applicant(s)/Patent under
Reexamination

NOVAK, W. THOMAS

Art Unit

2851

SEARCHED

Class	Subclass	Date	Examiner
355	53	6/30/2005	VHN
355	72, 73	6/30/2005	VHN
355	75, 76	6/30/2005	VHN
355	40, 67	6/30/2005	VHN
350	399, 400	7/12/2005	VHN
250	548	7/12/2005	VHN
356	400, 401	7/12/2005	VHN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLUS search	6/24/2005	VHN
(height altitude level tilt) sensor and wafer (stage chuck); "surface profile" or "ideal height data"	6/24/2005	VHN
(measuring station) with (first second other); (measuring station) and (wafer stage, height sensor)	7/12/2005	VHN
Consulted with Hung Nguyen	7/7/2005	VHN